項目 ITEM	規格 SPECIFICATION		檢測方法及條件 TEST METHOD AND CONDITION
10. 高溫負荷 (壽命試驗) High temperature Loading (Loading life)	外觀 Appearance	無顯著之異常。 No marked defect.	<500VDC在試驗溫度下連續施加2倍W.V.≥500VDC,在試驗溫度下連續施加1倍W.V.(充放電電流50mA以下)1000(+48-0)小時 <500VDC apply 2 times rated voltage,≥500VDC apply 1 times rated voltage,at maximum operating temperature for 1000(+48-0)hours
		T.C.: ±7.5% or ±0.75PF;	
	靜電容量變化率 Capacitance change	HIK、半導體類(S.C.): Y5E、Y5P、BN:±10%; X7R、Y5R:±15%; Y5T、Y5U、Z5U:±20%; Z5V、Y5V:±30%。	Test temp.: T.C.、Y5E、Y5P、BN、Y5R、Y5T、Y5U、Z5U、Y5V、Z5V: 85℃ ±5℃ NPO N750、X7R: 125℃ ±5℃ Change or discharge current shall not exceed 50mA..
	Q or DF	T.C. C<30PF: Q≥200+10xC C≥30PF: Q≥500	試驗後：取出於室溫中，T.C.類需放置24小時以上方可測定；HIK、半導體類需放置48小時以上方可測定。
		HIK. Y5E、Y5P、X7R、Y5U、Z5U DF≤5% Y5V、Z5V DF≤7.5% BN、Y5T DF≤1% Y5R DF≤0.5%	Capacitor shall be measured after leaving at room temperature T.C.:24Hr HIK、S.C.:48Hr
		半導體（S.C.）: Y5P、Y5U DF≤7.5% Y5V Df≤10%	
	絕緣電阻 Insulation resistance	T.C.:1000MΩ min HIK:500MΩ min S.C.:25MΩ x UF min	
11. 端子強度 Strength of lead	抗拉強度 Pull	導綫不斷裂，電容器本體不破損。 Lead wire shall not cut off and capacitor shall not be broken.	垂直固定被測物本體，引線向下，負荷施力方向爲端線引出方向，施加負荷爲1.0kg，時間爲5秒 As a figure fix the body of capacitor, apply a tensile weight gradually to each lead in the radial direction of capacitor up to 1.0kg,and keep it for 5 secretary..
	彎曲強度 Bending		固定被測物，施加0.5kg於端子引綫間并彎曲90°，回復原來之位置，并反向彎曲90°，1次彎曲時間爲5秒。 Each lead wire shall be subjected to 0.5kg weight and then a 90° bent, in one direction, return to original position and then a 90° bent in the opposite direction at the rate of onebent in 5 seconds..
11. 儲存 Storage	必須存放于室溫5-35℃中且濕度≤75%的室內，在此儲存條件下可保證3年的壽命。 Store all capacitors indoors at temperature of 5-35℃, humidity≤75%. They are warranted for a period of 3 years from the date of manufacture.		